

**Abstract of the Disclosure**

**[0026]** An apparatus and method for trouble shooting devices contained within a digital electronic system using external test equipment and scan module contained within the devices. Upon receipt of an external event trigger by the scan module, the operations of the device are halted. The contents of the flip-flops contained within the device are held constant. Thereafter, the contents of the flip-flops may be transmitted serially from the device to the external test equipment. Communication lines between the external test equipment and the device may be embedded within a baseboard in which the devices are attached.